APT40DQ120SG Datasheet Ultrafast Soft Recovery Rectifier Diode

June 2018





Contents

1	Revis	sion History	. 1
	1.1	Revision A	1
2	Prod	luct Overview	2
	2.1	Features	2
		Benefits	
		Applications	
3	Elect	rical Specifications	3
		Absolute Maximum Ratings	
	3.2	Electrical Performance	3
	3.3	Dynamic Characteristics	4
	3.4	Typical Performance Curves	4
	3.5	Reverse Recovery Overview	6
4		age Specification	
	4.1	Package Outline Drawing	8



1 Revision History

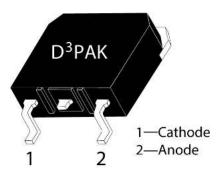
The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision A

Revision A was published in June 2018. It is the first publication of this document.



2 Product Overview



2.1 Features

The following are key features of the APT40DQ120SG device:

- Ultra-fast recovery times
- Soft recovery characteristics
- Low forward voltage
- Low leakage current
- Avalanche energy rated
- RoHS compliant

2.2 Benefits

The following are benefits of the APT40DQ120SG device:

- Higher switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

2.3 Applications

The APT40DQ120SG device is designed for the following applications:

- Power Factor Correction (PFC)
- Anti-parallel diode
 - Switch-mode power supply
 - Inverters/converters
 - Motor controllers
- Freewheeling diode
 - Switch-mode power supply
 - Inverters/converters
- Snubber/clamp diode



3 Electrical Specifications

This section shows the electrical specifications for the APT40DQ120SG device.

3.1 Absolute Maximum Ratings

The following table shows the absolute maximum ratings for the APT40DQ120SG device.

All ratings: Tc = 25 °C unless otherwise specified.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VR	Maximum DC reverse voltage	1200	V
V _{RRM}	Maximum peak repetitive reverse voltage	1200	_
V _{RWM}	Maximum working peak reverse voltage	1200	_
I _{F(AV)}	Maximum average forward current (Tc = 112 °C, duty cycle = 0.5)	40	Α
I _{F(RMS)}	RMS forward current	63	_
Iгsм	Non-repetitive forward surge current (T _J = 45 °C, 8.3 ms)	210	
EAVL	Avalanche energy (1 A, 40 mH)	20	mJ
Tı , Tstg	Operating and storage temperature range	-55 to 175	°C
TL	Lead temperature for 10 seconds	300	_

The following table shows the thermal and mechanical characteristics of the APT40DQ120SG device.

Table 2 • Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit
Reлc	Junction-to-case thermal resistance			0.61	°C/W
Wτ	Package weight		0.14		OZ
			4.0		g

3.2 Electrical Performance

The following table shows the static characteristics of the APT40DQ120SG device.

Table 3 • Static Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
VF	Forward voltage	I _F = 40 A		2.8	3.4	_ V _
		I _F = 80 A		3.4		
		I _F = 40 A, T _J = 125 °C		2.1		
Irm	Maximum reverse leakage current	V _R = 1200 V			100	μΑ
		V _R = 1200 V, T _J = 125 °C			500	-
Cı	Junction capacitance, V _R = 200 V			36		pF



3.3 Dynamic Characteristics

The following table shows the dynamic characteristics of the APT40DQ120SG device.

Table 4 • Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Uni
trr	Reverse recovery time	I _F = 1 A, di _F /dt = -100 A/μs		26		ns
		$V_R = 30 \text{ V}, T_J = 25 \text{ °C}$				
trr	Reverse recovery time	I _F = 40 A, di _F /dt = -200 A/μs V _R = 800 V, T _C = 25 °C		350		_
Qrr	Reverse recovery change			570		nC
Irrm	Maximum reverse			4		Α
	recovery current					
trr	Reverse recovery time	I _F = 40 A, di _F /dt = -200 A/μs		430		ns
Qrr	Reverse recovery charge	V _R = 800 V, T _C = 125 °C		2200		nC
IRRM	Maximum reverse			9		Α
	recovery current					
trr	Reverse recovery time	I _F = 40 A, di _F /dt = -1000 A/μs		210		ns
Qrr	Reverse recovery change	V _R = 800 V, T _C = 125 °C		3400		nC
Irrm	Maximum reverse	=		29		Α
	recovery current					

3.4 Typical Performance Curves

This section shows the typical performance curves for the APT40DQ120SG device.

Figure 1 • Maximum Transient Thermal Impedance

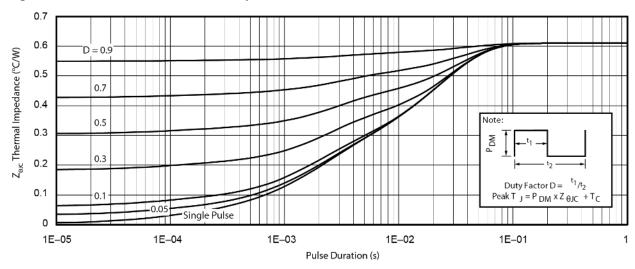




Figure 2 • Forward Current vs. Forward Voltage

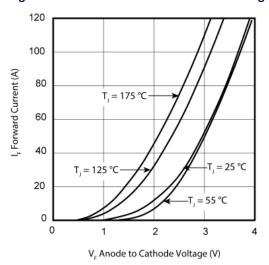


Figure 4 • Qrr vs. Current Rate of Change

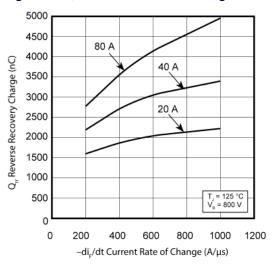


Figure 6 • Dynamic Parameters vs. Junction Temperature

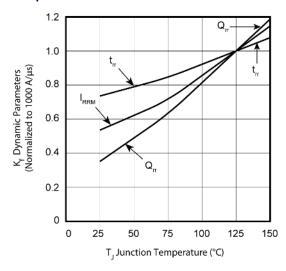


Figure 3 • trr vs. Current Rate of Change

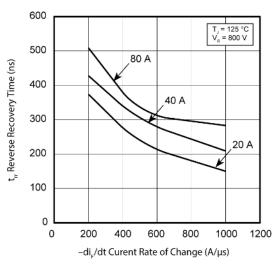


Figure 5 • IRRM vs. Current Rate of Change

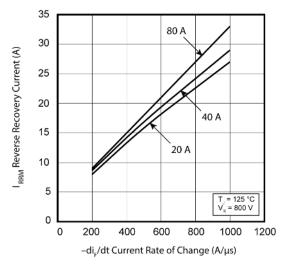


Figure 7 • Maximum Average Forward Current vs. Case Temperature

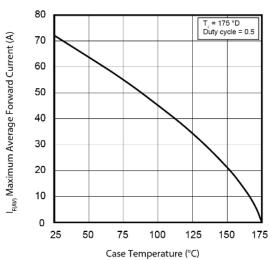
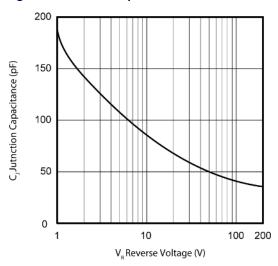




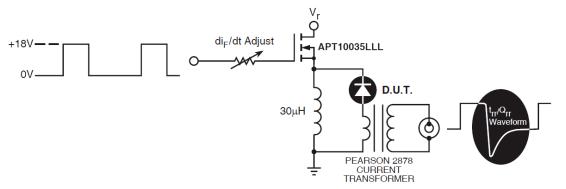
Figure 8 • Junction Capacitance vs. Reverse Voltage



3.5 Reverse Recovery Overview

The following illustration shows the diode test circuit for the APT40DQ120SG device.

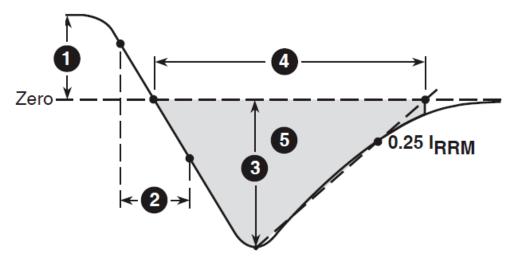
Figure 9 • Diode Test Circuit



The following illustration shows the diode reverse recovery waveform and definitions for the APT40DQ120SG device.



Figure 10 • Diode Reverse Recovery Waveform and Definitions



- 1. IF—Forward conduction current.
- 2. di_F/dt—Rate of diode current change through zero crossing.
- 3. IRRM—Maximum reverse recovery current.
- 4. t_{rr}—Reverse recovery time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25 I_{RRM} passes through zero.
- 5. Q_{rr}—Area under the curve defined by I_{RRM} and t_{rr}.



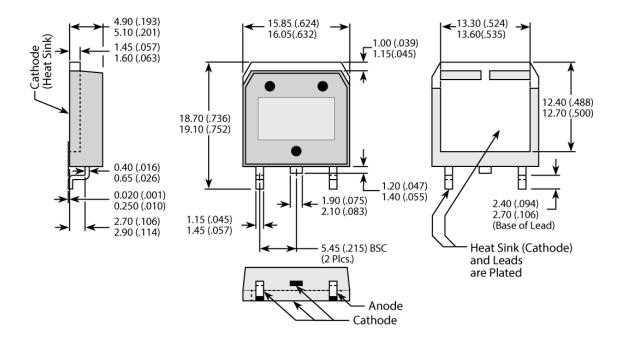
4 Package Specification

This section shows the package specification for the APT40DQ120SG device.

4.1 Package Outline Drawing

This section shows the D³PAK package drawing of the APT40DQ120SG device. Dimensions are in millimeters and (inches).

Figure 11 • Package Outline Drawing







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